

INTERNATIONAL STANDARD



**Display lighting unit –
Part 2-5: Measurement method for optical quantities of non-planar light sources**



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INTERNATIONAL ELECTROTECHNICAL COMMISSION

DISPLAY LIGHTING UNIT –

**Part 2-5: Measurement method for optical quantities
of non-planar light sources**

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International Standard IEC 62595-2-5 has been prepared by IEC technical committee 110: Electronic displays.

The text of this International Standard is based on the following documents:

FDIS	Report on voting
110/1296/FDIS	110/1320/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62595 series, published under the general title *Display lighting unit*, can be found on the IEC website.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific document. At this date, the document will be

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- withdrawn,
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INTRODUCTION

The recent introduction of curved OLED TVs, and the expected rapid spread of flexible displays in portable devices, highlights the necessity of new measurement methods. In recent years flexible displays have been integrated into products such as cellular phones and wearable devices [1] to [5]¹. Development and integration of flexible displays have increased the application of curved devices, for example distinct or curved-back large-size wall displays, foldable signage displays, and commercial wearable or handheld devices. The measurement of optical characteristics of displays with radii larger than 35 mm has been documented.

Recently flexible light sources (LSs) have been used for general lighting applications and as light source for flexible non-emissive displays. Since bending a planar lighting unit alters the optical properties of the unit, assessment of the optical performance of the lighting units in a curved state, i.e., concave or convex condition, is indispensable for manufacturing companies.

A light source can be a planar or non-planar (continuous multiple curvatures), i.e., convex (outer light emitting surface of a curvature), or concave light source (inner light emitting surface of a curvature). When a light source is bent the LS is under strain, i.e., tension or depression, the optical characteristics differ from that of a planar LS. A non-planar LS may have local curvatures on its surface with different surface normal from position to position. Such an LS can be a semiconductor light-emitting diode (LED, OLED, polymer LED (PLED)) or a phosphor excited type using a pump source. An LS can have a narrow-band radiation or more than one narrow band emission.

Issues concerning flexible light sources with surface curvatures, which are different from those issues concerning displays (e.g., resolution, contrast, lateral and directional characteristics or directions of viewing), hitherto have not been documented.

Since the characteristics of a non-planar light source (NPLS) change with the decreasing radius of the curvature, the optical characteristics of LS such as lateral and directional luminance and luminance variations, lateral and directional chromaticity distributions and their variations, luminous intensity distribution, and luminous flux, will be measured and evaluated.

This document establishes the measurement methods for cylindrical light sources that can be a base for the study of non-planar LS, which is assumed to be an integration of small areas. The fundamental element of such a surface can be a convex or a concave curvature with a first order of radius, i.e., a cylindrical shape, which is worth considering in this document.

In addition, a curved light source is used in a variety of conditions. Therefore, the optical measurements of an LS will be performed in a darkroom.

As in the measurement of planar LSs the following measurements are used for convex and concave LS measurements: 1) a lateral scanning measurement and 2) a directional scanning measurement. In the case of lateral scanning, the surface normal coincides with the optical axis of the light measurement device. In the case of directional scanning the local surface normal makes an angle with the optical axis of the measurement device.

Since the aperture of a light measurement device is not zero (non-zero aperture), there exist an optimized measurement distance and angle (i.e., 0,1°, 0,2°, 1°, and 2°) for the measurements. In the measurement of a cylindrical LS, a light measurement device which has sufficient depth-of-field or depth-of-focus is selected, because the measurement field on the LS has a three-dimensional geometry and is different from that of a plane.

¹ Numbers in square brackets refer to the Bibliography.

DISPLAY LIGHTING UNIT –

Part 2-5: Measurement method for optical quantities of non-planar light sources

1 Scope

This part of IEC 62595 specifies the measurement methods for measuring the optical characteristics of convex and concave cylindrical light sources. These non-planar light sources (NPLSs) can have either a continuous, distinct, segmented or block-wised light radiating surface, for example OLED panels, integrated LEDs, integrated mini-LEDs, micro-LEDs, laser diodes, each being either monochromatic or polychromatic.

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61747-6-2, *Liquid crystal display devices – Part 6-2: Measuring methods for liquid crystal display modules – Reflective type*

IEC 62595-2-1, *Display lighting unit – Part 2-1: Electro-optical measuring methods of LED backlight unit*

IEC 62595-2-3, *Display lighting unit – Part 2-3: Electro-optical measuring methods for LED frontlight unit*

IEC 62679-3-3, *Electronic paper displays – Part 3-3: Optical measuring methods for displays with integrated lighting units*

IEC 62922, *Organic light emitting diode (OLED) panels for general lighting – Performance requirements*

ISO/CIE 11664-3, *Colorimetry – Part 3: CIE tristimulus values*

ISO/CIE 19476, *Characterization of the performance of illuminance meters and luminance meters*

CIE S 017/E:2020, *International Lighting Vocabulary*

CIE 1931, *Colour space*